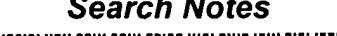


Search Notes	Application No.	Applicant(s)
	10/003,594	CHANG ET AL.
	Examiner	Art Unit
	Sargon N Nano	2157

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>